

Data Sheet January 2000 File Number 3414.3

75A, 1200V Hyperfast Diode

The RHRG75120 is a hyperfast diode with soft recovery characteristics (t_{rr} < 85ns). It has half the recovery time of ultrafast diodes and is silicon nitride passivated ion-implanted epitaxial planar construction.

This device is intended for use as a freewheeling/clamping diode and rectifier in a variety of high frequency switching power supplies and other power switching applications. Its low stored charge and hyperfast soft recovery characteristic minimize ringing and electrical noise in many power switching circuits, thus reducing power loss in the switching transistors.

Formerly developmental type TA49042.

Ordering Information

PART NUMBER	PACKAGE	BRAND	
RHRG75120	TO-247	RHRG75120	

NOTE: When ordering, use the entire part number.

Symbol



Features

•	Hyperfast with Soft Recovery <85ns
•	Operating Temperature
•	Reverse Voltage

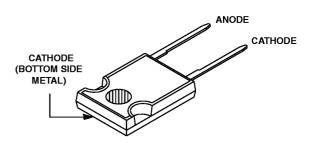
- · Avalanche Energy Rated
- · Planar Construction

Applications

- · Switching Power Supplies
- · Power Switching Circuits
- General Purpose

Packaging

JEDEC STYLE TO-247



Absolute Maximum Ratings $T_C = 25^{\circ}C$ RHRG75120 UNITS 1200 1200 DC Blocking VoltageV_R 1200 75 $(T_C = 42^{\circ}C)$ 150 Α (Square Wave, 20kHz) 500 Α (Halfwave, 1 Phase, 60Hz) 190 W Avalanche Energy (See Figures 7 and 8) EAVL 50 mJ -65 to 175 °C

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

SYMBOL	TEST CONDITION	MIN	ТҮР	MAX	UNITS
V _F	I _F = 75A	-	-	3.2	V
	I _F = 75A, T _C = 150 ^o C	-	-	2.6	V
I _R	V _R = 1200V	-	-	250	μΑ
	V _R = 1200V, T _C = 150 ^o C	-	-	2	mA
t _{rr}	l _F = 1A, dl _F /dt = 100A/μs	-	-	85	ns
	I _F = 75A, dI _F /dt = 100A/μs	-	-	100	ns
t _a	I _F = 75A, dI _F /dt = 100A/μs	-	60	-	ns
t _b	l _F = 75A, dl _F /dt = 100A/μs	-	25	-	ns
R _{eJC}		-	-	0.8	°C/W

DEFINITIONS

 V_F = Instantaneous forward voltage (pw = 300 μ s, D = 2%).

I_R = Instantaneous reverse current.

 t_{rr} = Reverse recovery time (See Figure 6), summation of $t_a + t_b$.

 t_a = Time to reach peak reverse current (See Figure 6).

t_b = Time from peak I_{RM} to projected zero crossing of I_{RM} based on a straight line from peak I_{RM} through 25% of I_{RM} (See Figure 6).

 $R_{\theta JC}$ = Thermal resistance junction to case.

pw = Pulse width.

D = Duty cycle.

Typical Performance Curves

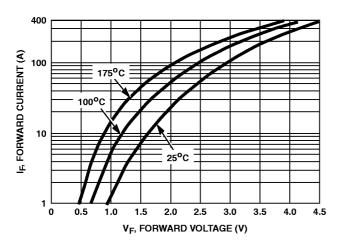


FIGURE 1. FORWARD CURRENT vs FORWARD VOLTAGE

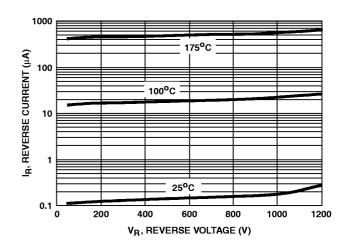


FIGURE 2. REVERSE CURRENT vs REVERSE VOLTAGE

Typical Performance Curves (Continued)

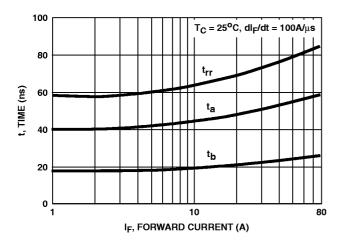


FIGURE 3. t_{rr}, t_a AND t_b CURVES vs FORWARD CURRENT

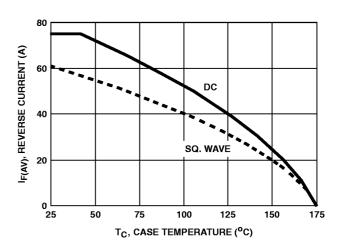


FIGURE 4. CURRENT DERATING CURVE

Test Circuits and Waveforms

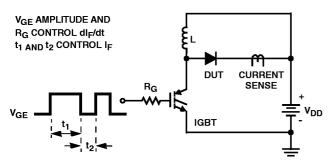


FIGURE 5. t_{rr} TEST CIRCUIT

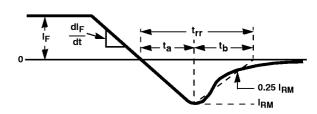


FIGURE 6. t_{rr} WAVEFORMS AND DEFINITIONS

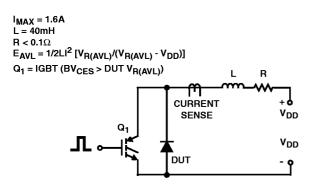


FIGURE 7. AVALANCHE ENERGY TEST CIRCUIT

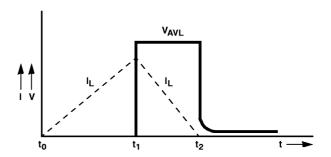


FIGURE 8. AVALANCHE CURRENT AND VOLTAGE WAVEFORMS

All Intersil semiconductor products are manufactured, assembled and tested under ISO9000 quality systems certification.

Intersil semiconductor products are sold by description only. Intersil Corporation reserves the right to make changes in circuit design and/or specifications at any time without notice. Accordingly, the reader is cautioned to verify that data sheets are current before placing orders. Information furnished by Intersil is believed to be accurate and reliable. However, no responsibility is assumed by Intersil or its subsidiaries for its use; nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Intersil or its subsidiaries.

For information regarding Intersil Corporation and its products, see web site www.intersil.com